

Search Notes

Application/Control No.

10/617,055

Examiner

Emeka Ebirim

Applicant(s)/Patent under
Reexamination

LEE ET AL.

Art Unit

2166

SEARCHED

| Class | Subclass | Date | Examiner |
|-------|----------|----------|----------|
| 707 | 100 | 2/6/2006 | EE |
| 700 | 108 | 2/6/2006 | EE |
| 715 | 736 | 2/6/2006 | EE |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
|-------|----------|------|----------|
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
|--------------------------------|----------|------|
| EAST | 2/6/2006 | EE |
| Consulted Pham Khanh (Primary) | 2/6/2006 | EE |
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